

**Search Notes**

Application No.

09/526,173

Examiner

A. Dexter Tugbang

Applicant(s)

IMAMURA, ISAO

Art Unit

3729

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	(above)	7/12/2004	ADT
Updated	(above)	12/23/2004	ADT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
29	All	12/23/2004	ADT
430	Listed	↓	↓
347	Above	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

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SEARCHED			
Class	Sub.	Date	Exmr.
29	830.1 25,35 611 830 D16 16	4/19/02	NOT
430	5 320 325 326 396	4/20/02	NOT
347	44 47 63 65		
updated (above)		12/10/02	NOT
updated (above)		12/15/03	NOT

INTERFERENCE SEARCHED			
Class	Sub.	Date	Exmr.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	Date	Exmr.
Consulted J. McPherson Primary Class 430	4/19/02	
Reviewed personal collection of NPL - IEEE Journal of Microelectro- mechanical Systems	4/20/02	
Consulted C. Hollocher, Primary Class 347	12/10/02	NOT
Text Search GPT (printout attached herein).		

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